

Notice of References Cited

Application/Control No.

10/550,800

Applicant(s)/Patent Under
Reexamination
NAGAI ET AL.

Examiner

Jack I. Berman

Art Unit

2881

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,409,683 A	04-1995	Tillotson et al.	423/338
*	B	US-6,320,937 B1	11-2001	Mochizuki, Takayasu	378/143
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NON-PATENT DOCUMENTS

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	U	Choi et al., "Detailed space-resolved characterization of a laser-plasma soft-x-ray source at 13.5-nm wavelength with tin and its oxides", Journal of the Optical Society of America, Vol. 17, No. 9, September 2000, pages 1616-1625.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.